

Form PTO-1449

U.S. DEPARTMENT OF COMMERCE  
PATENT AND TRADEMARK OFFICEATTY. DOCKET NO.  
MI22-1940SERIAL NO.  
10/087,558LIST OF ART CITED BY APPLICANT  
(Use several sheets if necessary)

APPLICANT: Micron Technology, Inc.

FILING DATE  
February 28, 2002GROUP  
1763

## U.S. PATENT DOCUMENTS

*Examiner's Initials		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
<i>TR</i>	AA	2003/0003697A1	01-2003	Agarwal et al.			Aug. 21, 2002
	AB	2003/0001190A1	01-2003	Basceri et al.			Aug. 26, 2002
	AC	2002/0037630A1	03-2002	Agarwal et al.			Oct. 29, 2001
	AD	6,787,185 B2	09-2004	Derderian et al.			
	AE	6,765,250 B2	07-2004	Doan et al.			
	AF	6,746,934 B2	06-2004	Sandhu et al.			
	AG	6,689,624 B2	02-2004	Doan et al.			
	AH	6,653,154 B2	11-2003	Doan et al.			
<i>V</i>	AI	6,627,260 B2	09-2003	Derderian et al.			

## FOREIGN PATENT DOCUMENTS

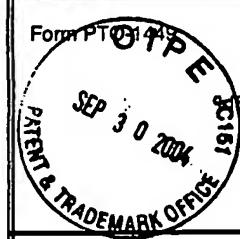
		Document Number	Date	Country	Class	Subclass	Translation	
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## OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)

	AM		
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EXAMINER: <i>Derderian</i>	DATE CONSIDERED	<i>5/17/07</i>	

\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Form PTO-1449 <i>O I P E</i> SEP 3 0 2004 U.S. PATENT & TRADEMARK OFFICE		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. MI22-1940		SERIAL NO. 10/087,558			
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*Examiner's Initials		Document Number	Date	Name		Class	Subclass	Filing Date If Appropriate	
<i>TR</i>	AM	6,596,636 B2	07-2003	Sandhu et al.					
	AB	6,596,583 B2	07-2003	Agarwal et al.					
	AC	6,559,472 B2	05-2003	Sandhu et al.					
	AD	6,541,353 B1	04-2003	Sandhu et al.					
	AE	6,534,357 B1	03-2003	Basceri et al.					
	AF	6,458,416 B1	10-2002	Derderian et al.					
	AG	6,420,230 B1	07-2002	Derderian et al.					
	AH	5,463,978	11-1995	Larkin et al.					
	AI	6,143,659	11-2000	Leem					
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EXAMINER <i>Jeff P.</i>		DATE CONSIDERED		5/17/07					
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<i>AM</i>	AA	6,478,872 B1	11-2002	Chae et al.			
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	AH						
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<i>AB</i>	AA	6,185,839 B1	02/2001	Kholodenko et al.	34	255	
<i>AB</i>	AB	6,245,151 B1	06/2001	Bhandari et al.	34	255	
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EV318282424 Sheet 1 of 1

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<i>AB</i>	AA	5,620,524	04/15/97	Fan et al.			
<i>AB</i>	AB	6,419,462 B1	07/16/02	Horie et al.			
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